Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
LP5009RUKR	WQFN	RUK	20	3000	330.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
LP5009RUKR	WQFN	RUK	20	3000	367.0	367.0	35.0

TAPE AND REEL INFORMATION





Marking picture	vendor Name	Part No.	Marking Rule
LP5009	ТІ	LP5009RUKR	the marking " LP5009" represents the device name, by identifying units marking LP5009 correctly to determine device

Component	Homogeneous Material Name.	Substance	CAS Number	Amount (mg)	Percentage %
Dand M/iro	Copper and Its Alloys	Copper	7440-50-8	0.081908	99.99878
Bond Wire	Precious Metals	Silver	7440-22-4	0.000001	0.001221
Die Attach Adhasive	Precious Metals	Silver	7440-22-4	0.206	80
Die Attach Adhesive	Thermoplastics	Ероху	85954-11-6	0.0515	20
	Copper and Its Alloys	Copper	7440-50-8	15.6032	97.52
Load Frame	Copper and Its Alloys	Iron	7439-89-6	0.368	2.3
Lead Frame	Copper and Its Alloys	Phosphorus	7723-14-0	0.0048	0.03
	Zinc and Its Alloys	Zinc	7440-66-6	0.024	0.15
	Nickel and Its Alloys	Nickel	7440-02-0	0.4756	95.12
Lead Frame Plating	Precious Metals	Gold	7440-57-5	0.0039	0.78
	Precious Metals	Palladium	7440-05-3	0.0205	4.1
	Other Inorganic Materials	Fused Silica	60676-86-0	8.12064	88
Mold Compound	Other Organic Materials	Chlorine	7782-50-5	0.000092	0.000997
	Other Plastics and Rubber	Carbon Black	1333-86-4	0.027684	0.3
	Thermoplastics	Ероху	85954-11-6	1.079584	11.699
Semiconductor Device	Ceramics / Glass	Doped Silicon	7440-21-3	0.569732	100

Basic Information	Result
Device Part Number	LP5009RUKR
Wafer fab information, process type and node	TI RFAB LBC9
Wafer process was qualified and released to production or not.	Mature
Products have been applied with this wafer process?	Yes
Is there any part from the same wafer process family have been used in customer?	YES
Wafer Process Capability(SPC)	Meet SPC Spec
Is there any wafer process CPK<1.33? If yes, please list it and provide the improvement plan.	NO
Chip ID:Do you have chip ID or die ID for this device?	NO
Assembly Factory, Package type	TI CDAT QFN
Package Size (Length*Width*Height)	3x3x0.8mm

Ball/Lead pitch	0.4MM	
Is there any part from the same package family h please list the part number.	ave been used in customer? If yes,	YES
Wire Bonding	Wire composition	Cu
(Only for Wire Bonding Package)	Wire diameter	0.96mil
Assembly Process Capability(SPC)		Meet spc spec
Is there any assembly process CPK<1.33? If yes, p improvement plan.	NO	
Range of Operation Temperature (Ta, Tj or Tc)	Ta: -40C~85C	
Storage Temperature range	-65 ~ 150C	
Storage limit	1years at customer side	
Max.Junctioin Temperature	125C	
IFR, Intrinsic Failure Rate, FIT	0.4FIT@60%CL	
MSL, Moisture Sensitive Level	MSL 2	
	Ѳја	53.7°C/W
Theta ja, jc and jb	Ѳјс	55.3 °C/W
	Øjb	27.4°C/W
	НВМ	4000
	CDM	1500
Latch-Up (At max. Ambient Temperature)		Meet qual test requirement
Test Factory		TI CDAT
If the chip is new process or new design, And som beyond JEDEC standard) had been down. Please s details.	ne Lifetime limit test(Test to fail or specify the test condition and result	NO
Wafer reliability Qualification Report, including: T	DDB, HCI, NBTI, PBTI, EM, SM .etc	YES
Package Qualification Report, including: PC, THB, Bend, PDT, PVT .etc	HAST, UHAST, HTSL, TC, BLTC, DT,	See Tl.com qual report
Device Qualification Report, including: ELFR, HTO CDM, LU .etc	See Tl.com qual report	
The device should be done reliability monitoring. Monitoring Report, including: PC, THB, HAST, UH,	Please provide the latest Reliability AST, TC, HTSL, HTOL .etc	ORT test based on package
Characterization report, follow JESD86		Refer to datasheet

Check Items for L	P5009RUKR	Result
Surface plating/	Composition	NIPDAU
	Thickness(µm)	Confidential
Basic metal		Cu
Package standard		JEDEC
Weight of compone	nt (g)	0.0266
Weight/ available P&	&P area≤0.06g/mm2	Yes
coplanarity	coplanarity during reflow process	refer to datasheet
Pin1 Mark point	Is there any pin1 Mark point in the top side of component?	Yes
	Is the pin1 mark point sole? (if not, pls. give the relationship between mark and terminals)	Yes
	Is there any specific location number of terminals in the component specification?	Yes
	Component orientation can be Identified by mounting machine or AOI?	Yes
seal	Is there any hole or gap in package body, flux enter package inside form the hole or gap, resulting in function fail	NO
exposed Non- insulator on component body	Whether there exists non-insulator at no soldering position. Are non-insulator and adjacent soldering pin the same circuit?	NO
	Have Dimension and Position of non-insulator been indicated in component spec.	Yes
Are matters RoHS co Compliant" in this fil Lead, Cd, Hg, Cr VI, F Lead-free	bmpliant listed below? (please refer to "sheet7 RoHS le) PBB, PBDE	Yes
Is it Halogen-free		Yes
Relative humidity (%	6)	≥20%&≤70%
Temperature (C)		≥-10C&≤35C

Maximum storage time (month)	Follow MSL rating rules Allowed 1 year stored at customer side
Packaging type	tape and real
Position of component pin 1 in packing	Q2
Packaging height(KO)	1.1
Packaging width(W)	12mm
component pitch:P1	8mm
ESD packaging	Yes
Rollover rate ≤0.05% in packing	Yes
Maximum component rotation for punched ≤10°	Yes
tray packing Baking conditions: 125°@24h	Yes
reel tape packing Baking conditions: 40°@192h	Yes
Can reel tape packing meet EIA 481 standard?	EIA
MSL	2
Baking requirement if moisture meets J-STD-033?	Yes
Moisture sensitive level at level 2 and level 2 above, moisture sensitive protection must include: moisture sensitive indicator card, desiccant, moisture sensitive grade logo	Yes
Manual soldering conditions: soldering iron tip temperature 400°G time≥5s。 Or hot gun temperature340°G time≥10s	Yes
Maximum soldering times ≥3	Yes
Can heat resistance of SMT components meet JSTD020D. (should focus on the classification of temperature and reflow profiles, that is table 4-1, 4-2 and 5-2, please refer to sheet6 J-STD-020D in this file)	Yes
Maximum pick-and-place pressure (N)	Yes
Whether the welding process and design requirements of component have all written to the component specifications	Yes
Whether Pad & stencil design as Mandatory requirements in component spec?	recommended
Whether the device has special requirements for the reflow temperature ramp-up rata and ramp-down rata? Customer follow J-STD-002 standard	No

Are there other mandatory requirements in component spec?	No
Solder ability test report	Yes
Board level reliability test report	No

Texas Instruments Qualification Summary

Quality and reliability are built into TI's culture, with the goal of providing customers high quality products. TI's semiconductor technologies are developed with a minimum goal of fewer than 50 Failures in Time (FIT) at 100,000 Power-On-Hours at 105C junction temperature. TI builds simulations, accelerated testing, and robustness evaluations into the product development process. During the product development process, TI carefully assesses silicon process reliability, package reliability, and silicon/package interaction.

TI also evaluates manufacturability of the device to verify a robust silicon and assembly flow to enable continuity of supply to customers. Non-Automotive devices are qualified with industry standard test methodologies performed primarily to the intent of the Joint Electron Devices Engineering Council (JEDEC). TI qualifies new devices, significant changes, and product families based on JEDEC JESD47. The data shown is representative of the material sets, processes, and manufacturing sites used by the device family.

Qualification summary for:	LP5009RUKR
Report date:	08/27/2020

Stress	Reference	Min lot qty	SS / lot	Condition	Duration	Result
HTOL	JESD22-A108	3	77	Life test, 125C	1000 hours	Pass
HTSL	JESD22-A103	3	25	High temp storage ba ke 150C	1000 hours	Pass
AC/UHAST	JESD22-A102/JESD2 2-A118	3	25	Autoclave 121C or un biased HAST 130C / 8 5% RH	96 hours	Pass
THB/HAST	JESD22-A101/JESD2 2-A110	3	25	THB 85C/85%RH or H AST 130C/110C/85% RH	1000 hours or 96 hou rs	Pass
TC	JESD22-A104	3	25	Temperature cycle -6 5/150C	500 cycles	Pass
SD	J-STD-002	3	22	Per specification	>95% lead coverage	Pass
НВМ	JS-001	1	3	ESD - HBM	Classification	See data sheet

CDM	JESD22-C101	1	3	ESD - CDM	Classification	See data sheet
LU	JESD78	1	3	Latch-up	Per JESD78	Pass
MSL	J-STD-020	—	—	Per J-STD-020	Classification	See data sheet

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